



SPECIFICATION

PN: 8W10000J33XCT

深圳市晶科鑫实业有限公司

SHENZHEN CRYSTAL TECHNOLOGY INDUSTRIAL CO., LTD.

VER	DESIGNED	CHECKED	APPROVED
A1	邵丹斌	李相同	刘恩克

CUSTOMER APPROVAL

SPECIFICATION :		晶振 / 3225 TCXO / 10.000MHz	
SJK PN. :		8W10000J33XCT	
CUSTOMER PN. :			
CHECKED 1	CHECKED 2	APPROVED	DATE
Result: <input type="checkbox"/> PASS <input type="checkbox"/> FAIL <input type="checkbox"/> OTHER			

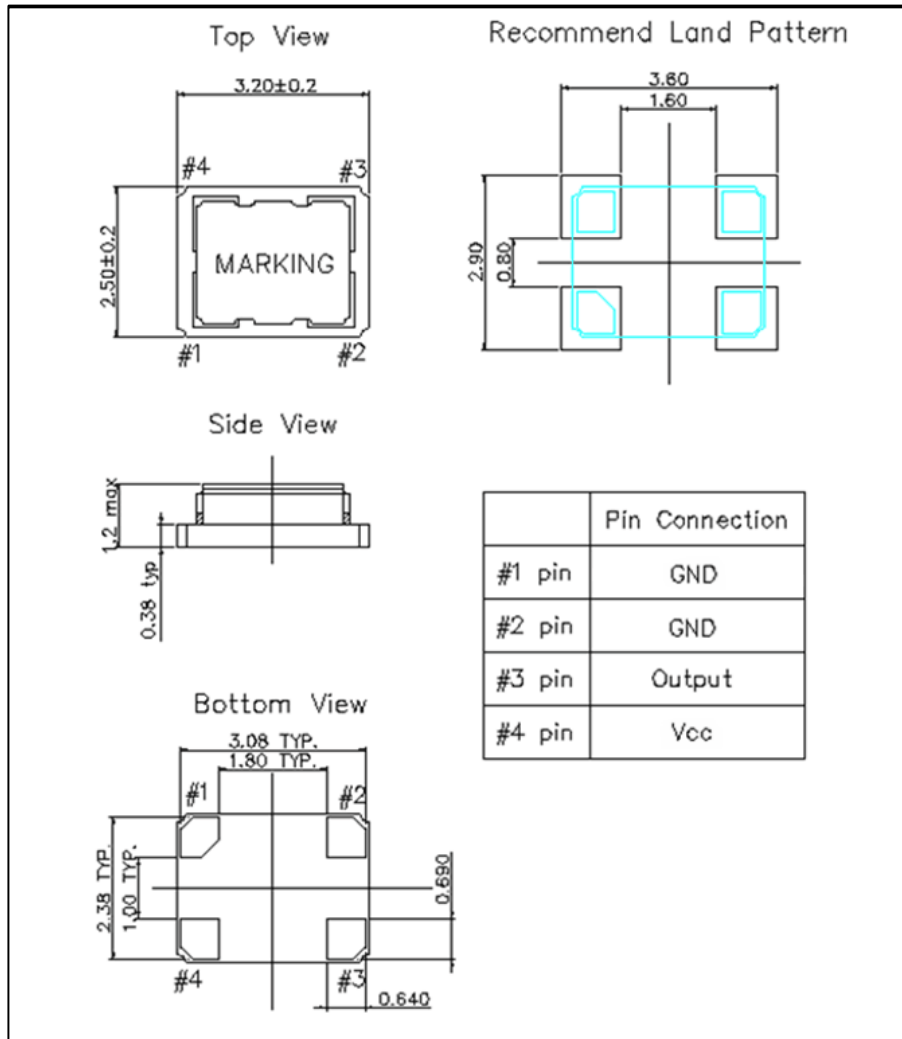
ELECTRICAL SPECIFICATIONS

Parameters		Condition	Electrical Specifications			
			MIN	TYP	MAX	UNITS
Nominal Frequency			10.000			MHZ
Operating Temperature Range			-40		85	°C
Supply Voltage			3.135	3.3	3.465	V
Supply Current					2	MA
Output Voltage			0.8			Vp-p
Output Type			Clipped sine wave			
Output Load		Resistance		10		kΩ
		Capacitance		10		pF
Frequency Tolerance		@25°C			±1.0	ppm
Frequency Stability	vs:Temperature	-40 ~ 85 °C			±0.5	ppm
	vs:Load	10kΩ/10pF ±10%			±0.2	ppm
	vs:Supply Voltage	Vcc±5%			±0.2	ppm
Storage Temperature			-40		85	°C
Start-up Time					2.0	ms
Harmonics					-5	dBc
SSB Phase Noise(@1KHz Carrier Offset)					-128	dBc/Hz
Aging					±1.0	ppm/5year

Crystal oscillator
SMD TCXO Module 3.2×2.5×1.2 7T Series



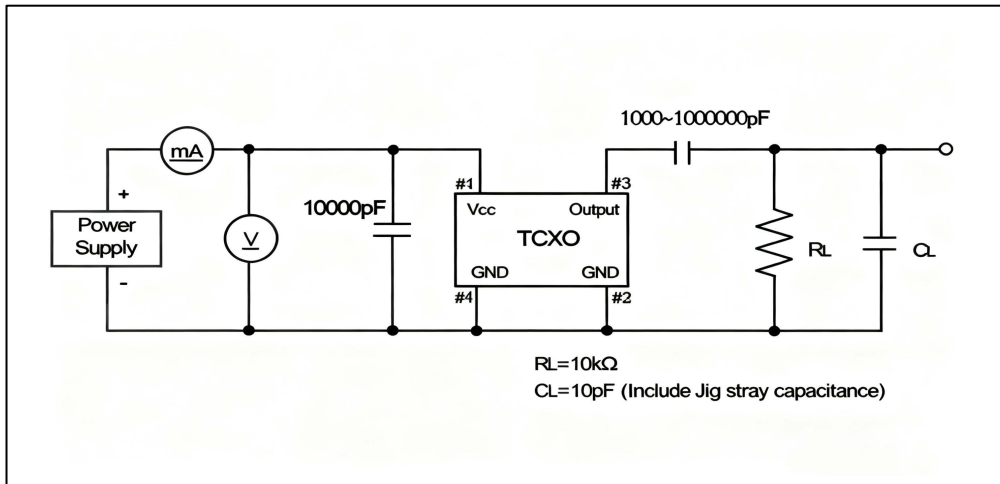
DIMENSION (Unit: mm)



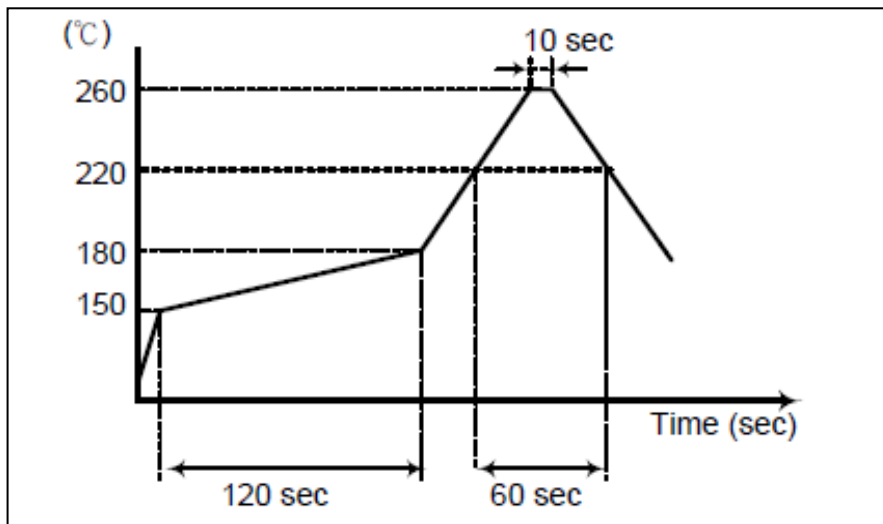
MARK



MEASUREMENT CIRCUIT

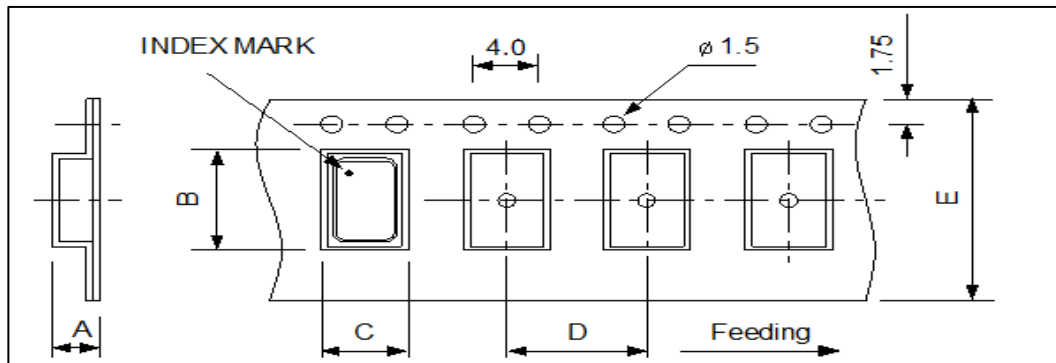


REFLOW CONDITION

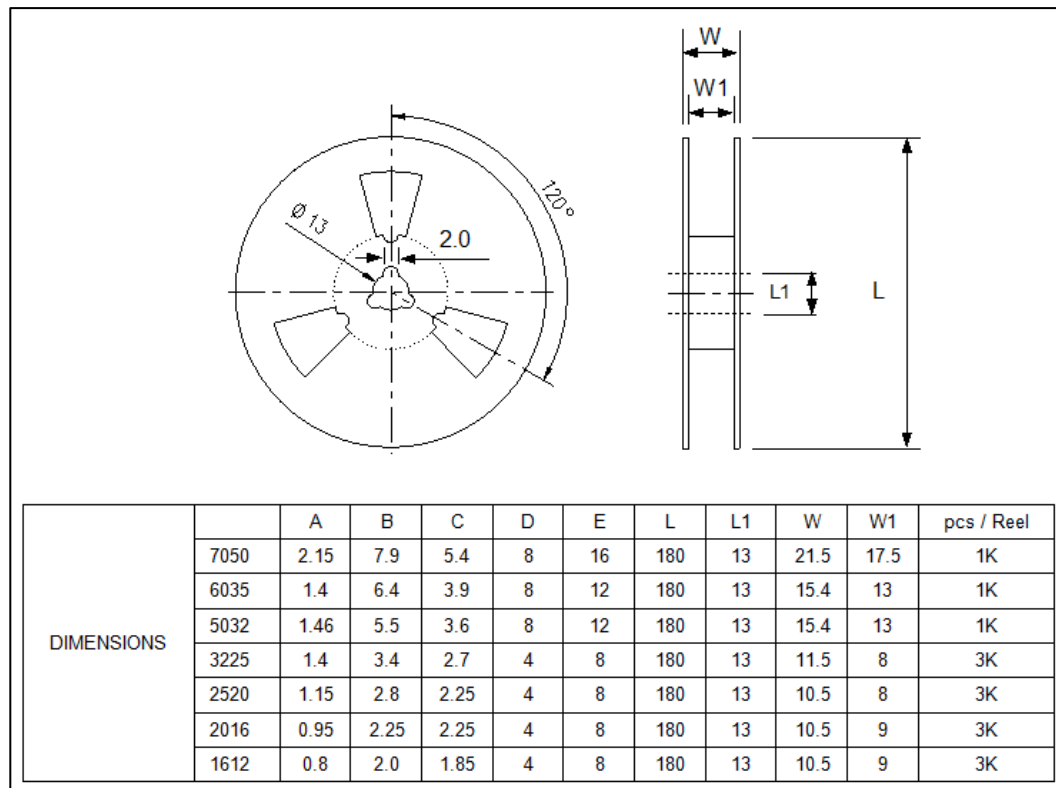


The reflow temperature profile may vary depending on the product model, specifications and frequency range. Refer to the individual product specifications for details

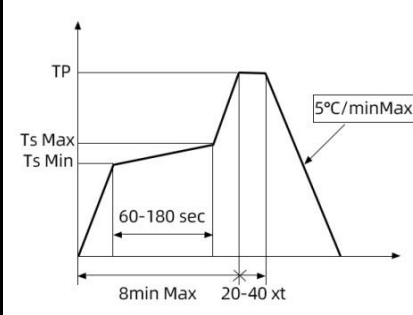
CARRIER TYPE



REEL



RELIABILITY TEST SPECIFICATIONS

Test item	Equipment	Condition	Specification
1.SOLDERABILITY TEST	SJK-REL001、RC-328A	<p>TP:260℃ TsMax: 200℃ TsMin: 150℃ 2 time</p> 	MIL-STD-883E Method 2003.7
2. HERMETICITY TEST	HELIOT-306S	Pressurized 0.4~0.5Mpa ethanol sealed tank for 10 minutes	MIL-STD-883E Method 1014.10
3. VIBRATION TEST	HG-V4、 S&A 250B	Enable Crystal(10g) from 10-55-10Hz,X、 Y、 Z horizontal,1 Minute vibration/time, 1time/ 2 hours.	MIL-STD-883E Method 2007.3
4. MECHANICAL SHOCK	HPC-200、 S&A 250B	Enable Crystal 50G(490m/s ²) time=11 ms speed=3.4 m/s half sine wave oscillation	JIS C6701
5. DROP TEST	HARD BOARD.S&A250B	75cm High,3 times on hard board	MIL-STD-202F Method 213B
6. HIGH&LOW TEMP STORAGE TEST(Static test)	H-PTH-80CK & HM101-3ABN, S&A 350B/250B	High temperature: 125℃±2℃,1000hr: Low temperature:-40℃±3℃,1000hrs	MIL-STD883C, METHOD 1011.8
7. TEMP &HUM CYCLING TEST	H-PTH-80CK CHAMBE, S&A 350B/250B	Temperature:-10℃±2℃~65℃±2℃,Humidity:93±3%,1 cycle need 24 hrs. 5cycles.	MIL-STD-883E Method 1005.8
8. HIGH TEM. & HUM.STORAGE TEST	H-PTH-80CK CHAMBE, S&A350B/250B	Temperature:85℃±2, Humidity:85+3,-2%,Store 96 hrs	JIS C6701
9. AGING TEST	H-PTH-80CK CHAMBE, S&A350B/250	Temperature:85℃±2, Store 1000 hrs	JIS C5023

REVISION RECORD (SJK-7T10000M3C04K0J1)

Rev	Revise contents	Reason	Reviser	Checked	Approved
A1	Initial released	--	贺丹斌	李相同	刘惠光